



AO8701, AO8701L (Green Product)

P-Channel Enhancement Mode Field Effect Transistor with Schottky Diode

General Description

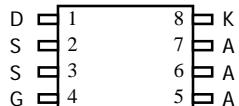
The AO8701 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. A Schottky diode is provided to facilitate the implementation of a bidirectional blocking switch. AO8701L (Green Product) is offered in a lead-free package.

Features

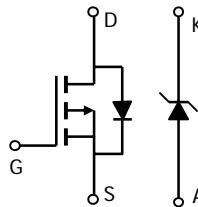
V_{DS} (V) = -30V
 I_D = -4.2A
 $R_{DS(ON)} < 50m\Omega$ ($V_{GS} = 10V$)
 $R_{DS(ON)} < 65m\Omega$ ($V_{GS} = 4.5V$)
 $R_{DS(ON)} < 120m\Omega$ ($V_{GS} = 2.5V$)

SCHOTTKY

V_{DS} (V) = 30V, I_F = 3A, $V_F=0.5V@1A$



TSSOP-8



Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

| Parameter | Symbol | MOSFET | Schottky | Units |
|---|----------------|------------|------------|-------|
| Drain-Source Voltage | V_{DS} | -30 | | V |
| Gate-Source Voltage | V_{GS} | ± 12 | | V |
| Continuous Drain Current ^A | I_D | -4.2 | | A |
| | | -3.5 | | |
| Pulsed Drain Current ^B | I_{DM} | -30 | | |
| Schottky reverse voltage | V_{KA} | | 30 | V |
| Continuous Forward Current ^A | I_F | | 3 | A |
| | | | 2 | |
| Pulsed Forward Current ^B | I_{FM} | | 40 | |
| Power Dissipation | P_D | 1.4 | 1.4 | W |
| | | 1 | 1 | |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | -55 to 150 | °C |

| Parameter: Thermal Characteristics MOSFET | Symbol | Typ | Max | Units |
|---|-----------------|-----|-----|-------|
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 73 | 90 | °C/W |
| Maximum Junction-to-Ambient ^A | | 96 | 125 | |
| Maximum Junction-to-Lead ^C | | 63 | 75 | |
| Thermal Characteristics Schottky | | | | |
| Maximum Junction-to-Ambient ^A | $R_{\theta JA}$ | 75 | 90 | °C/W |
| Maximum Junction-to-Ambient ^A | | 97 | 125 | |
| Maximum Junction-to-Lead ^C | | 63 | 75 | |

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|---|---|-------|-----------|------------------|
| STATIC PARAMETERS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D=-250\mu\text{A}, V_{GS}=0\text{V}$ | -30 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=-24\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$ | | -1 | -5 | μA |
| I_{GSS} | Gate-Body leakage current | $V_{DS}=0\text{V}, V_{GS}=\pm 12\text{V}$ | | | ± 100 | nA |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=-250\mu\text{A}$ | -0.7 | -1 | -1.3 | V |
| $I_{\text{D(ON)}}$ | On state drain current | $V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$ | -25 | | | A |
| $R_{\text{DS(ON)}}$ | Static Drain-Source On-Resistance | $V_{GS}=-10\text{V}, I_D=-4.2\text{A}$ $T_J=125^\circ\text{C}$ | | 43 | 50 | $\text{m}\Omega$ |
| | | $V_{GS}=-4.5\text{V}, I_D=-4\text{A}$ | | | 75 | $\text{m}\Omega$ |
| | | $V_{GS}=-2.5\text{V}, I_D=-1\text{A}$ | | 54 | 65 | $\text{m}\Omega$ |
| g_{FS} | Forward Transconductance | $V_{DS}=-5\text{V}, I_D=-5\text{A}$ | 7 | 11 | | S |
| V_{SD} | Diode Forward Voltage | $I_S=-1\text{A}, V_{GS}=0\text{V}$ | | -0.75 | -1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | -2.2 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C_{iss} | Input Capacitance | $V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$ | | 954 | | pF |
| C_{oss} | Output Capacitance | | | 115 | | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 77 | | pF |
| R_g | Gate resistance | $V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$ | | 6.1 | | Ω |
| SWITCHING PARAMETERS | | | | | | |
| Q_g | Total Gate Charge | $V_{GS}=-4.5\text{V}, V_{DS}=-15\text{V}, I_D=-4\text{A}$ | | 9.4 | | nC |
| Q_{gs} | Gate Source Charge | | | 2 | | nC |
| Q_{gd} | Gate Drain Charge | | | 3 | | nC |
| $t_{\text{D(on)}}$ | Turn-On DelayTime | $V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=3.6\Omega, R_{\text{GEN}}=6\Omega$ | | 6.3 | | ns |
| t_r | Turn-On Rise Time | | | 3.2 | | ns |
| $t_{\text{D(off)}}$ | Turn-Off DelayTime | | | 38.2 | | ns |
| t_f | Turn-Off Fall Time | | | 12 | | ns |
| t_{rr} | Body Diode Reverse Recovery Time | | $I_F=-4\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | 20.2 | | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | | $I_F=-4\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | 11.2 | | nC |
| SCHOTTKY PARAMETERS | | | | | | |
| V_F | Forward Voltage Drop | $I_F=1.0\text{A}$ | | 0.45 | 0.5 | V |
| I_{rm} | Maximum reverse leakage current | $V_R=30\text{V}$ | | 0.007 | 0.05 | mA |
| | | $V_R=30\text{V}, T_J=125^\circ\text{C}$ | | 3.2 | 10 | |
| | | $V_R=30\text{V}, T_J=150^\circ\text{C}$ | | 12 | 20 | |
| C_T | Junction Capacitance | $V_R=15\text{V}$ | | 37 | | pF |

A: The value of R_{JJA} is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design. The current rating is based on the $t \leq 10\text{s}$ thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C: The R_{JJA} is the sum of the thermal impedance from junction to lead R_{JL} and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80 μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

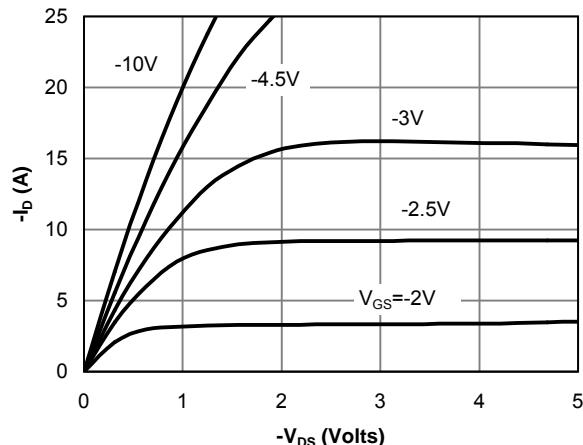


Fig 1: On-Region Characteristics

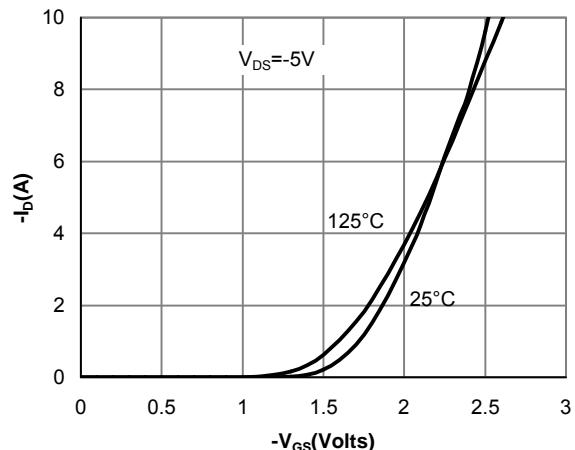


Figure 2: Transfer Characteristics

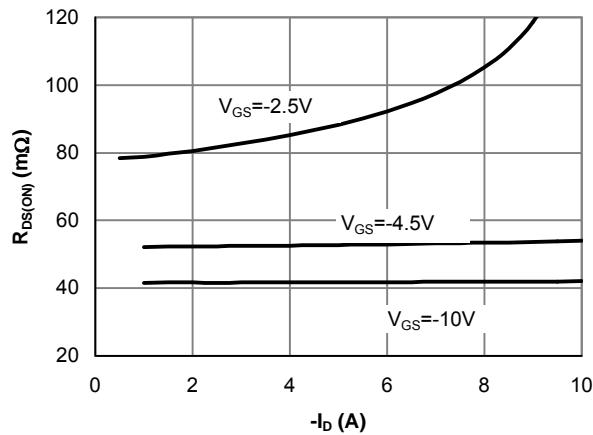


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

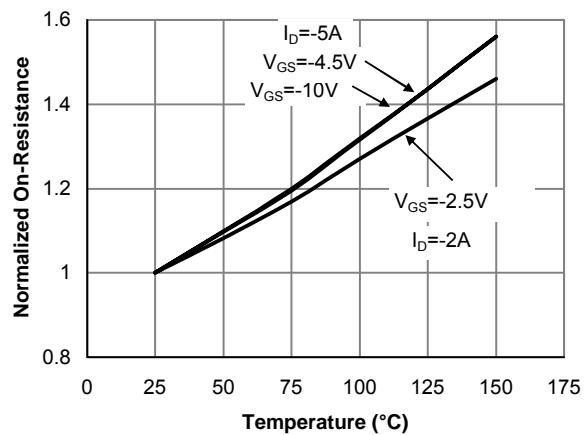


Figure 4: On-Resistance vs. Junction Temperature

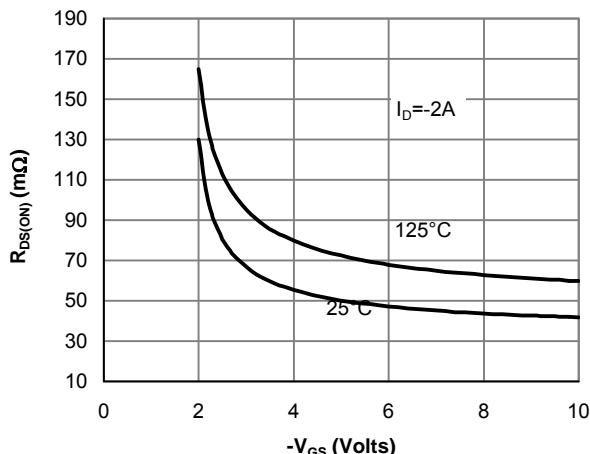


Figure 5: On-Resistance vs. Gate-Source Voltage

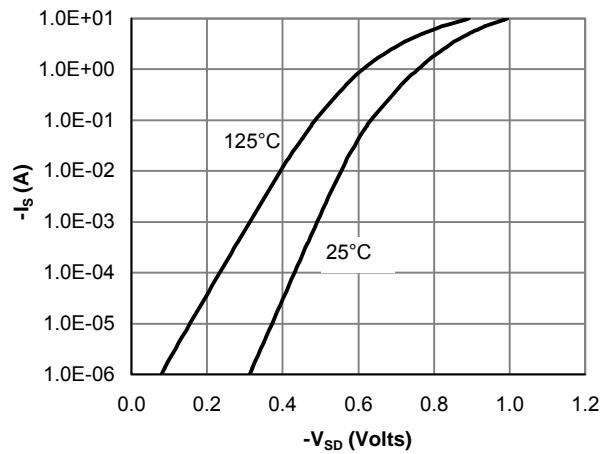


Figure 6: Body-Diode Characteristics

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

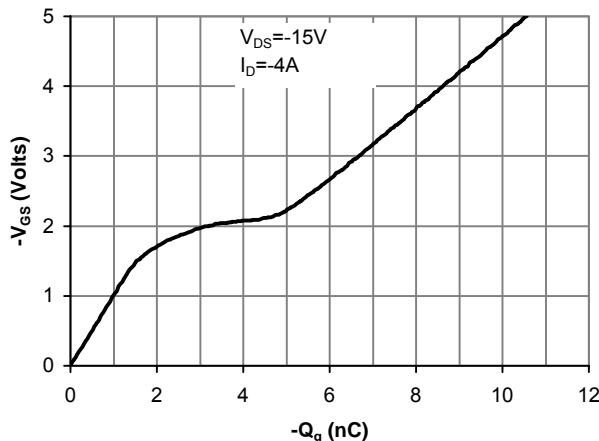


Figure 7: Gate-Charge Characteristics

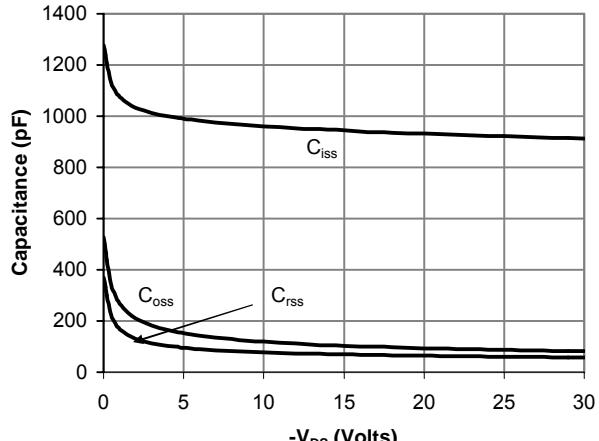


Figure 8: Capacitance Characteristics

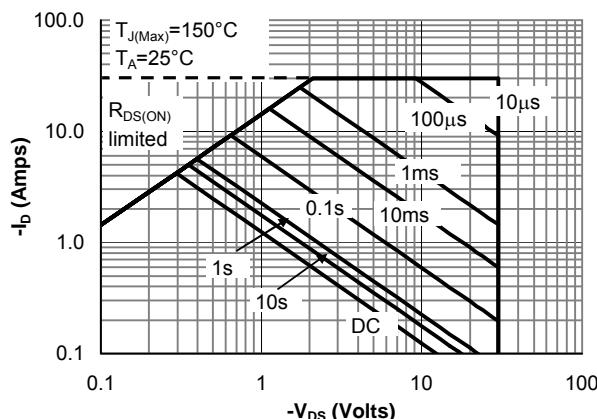


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

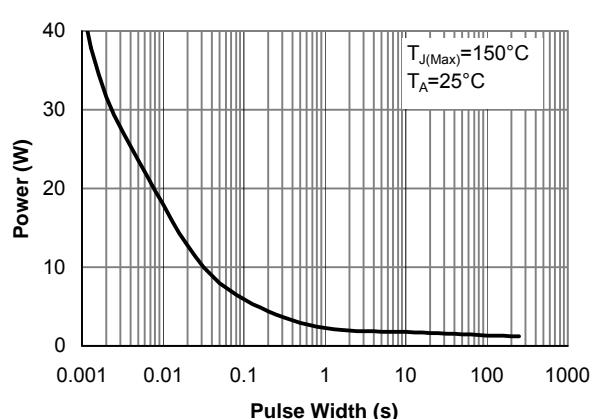


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

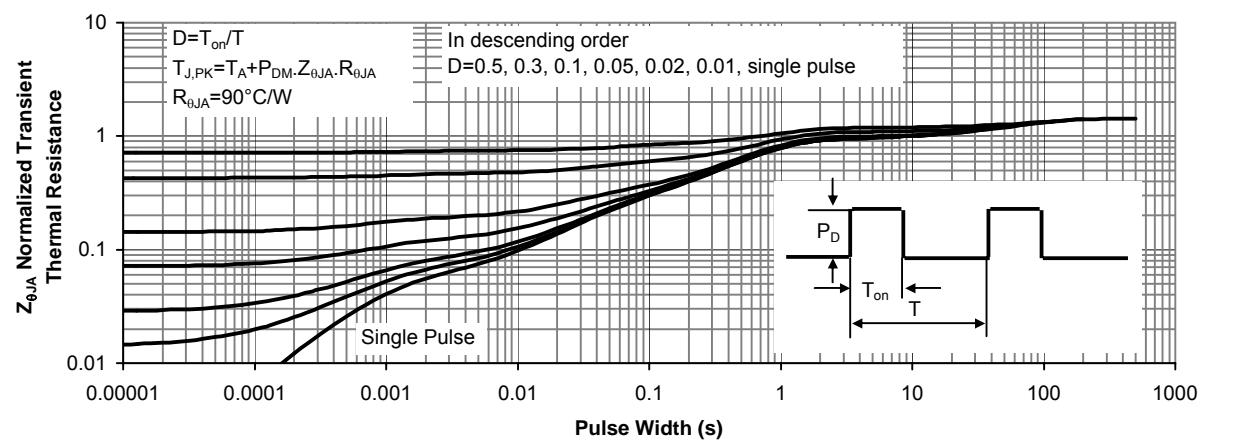


Figure 11: Normalized Maximum Transient Thermal Impedance

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: SCHOTTKY

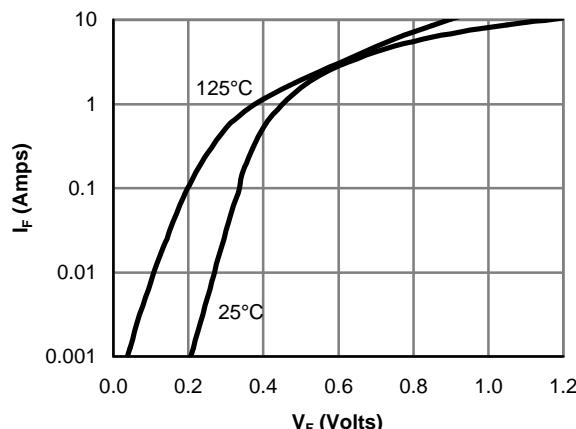


Figure 12: Schottky Forward Characteristics

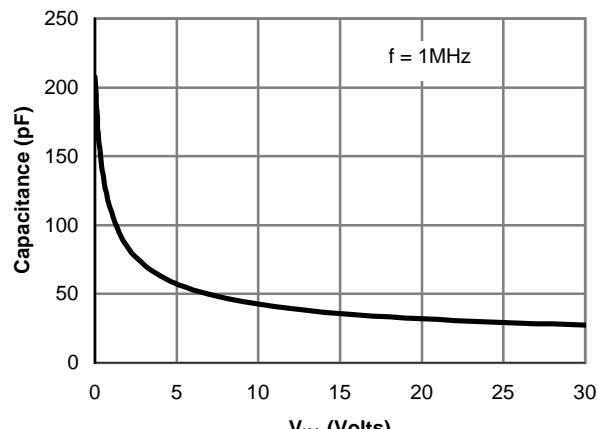


Figure 13: Schottky Capacitance Characteristics

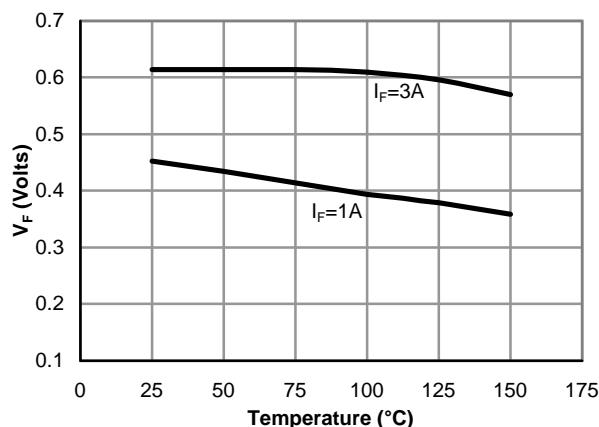


Figure 14: Schottky Forward Drop vs. Junction Temperature

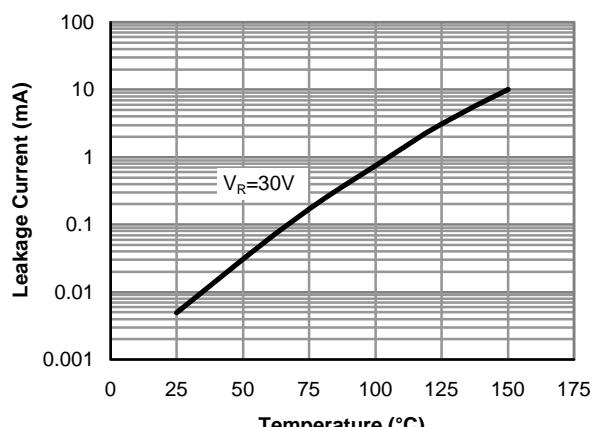


Figure 15: Schottky Leakage current vs. Junction Temperature

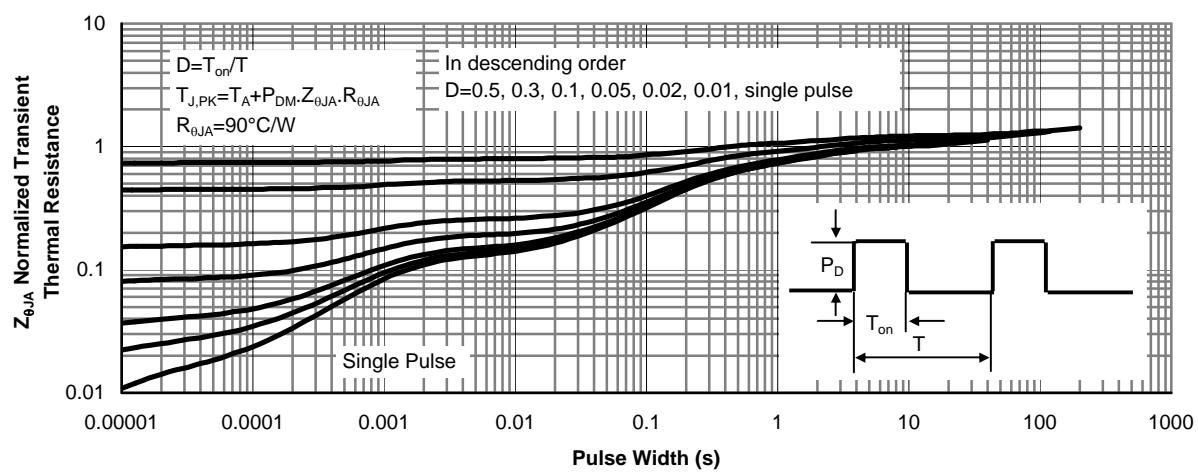


Figure 15: Schottky Normalized Maximum Transient Thermal Impedance